


<b>Search Notes</b>  	<b>Application/Control No.</b>  10544150	<b>Applicant(s)/Patent Under Reexamination</b>  SMITH, FRANCIS X.
	<b>Examiner</b>  SEAN M BASQUILL	<b>Art Unit</b>  1612

SEARCHED			
Class	Subclass	Date	Examiner
	Did not perform a class search		

SEARCH NOTES		
Search Notes	Date	Examiner
EAST	12/31/2008	TJM
PALM (inventor search)	12/31/2008	TJM
See EAST search history	5/18/2009	SB
See EAST Search history	10/22/2009	SB

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/TRISTAN J MAHYERA/  
Examiner,Art Unit 1615